

# MOSFET - Power, Single N-Channel 80 V, 2.1 m $\Omega$ , 203 A

# **NVMFS6H800N**

#### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- NVMFS6H800NWF Wettable Flank Option for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	80	V
Gate-to-Source Voltage	Э		V <sub>GS</sub>	±20	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	203	Α
Current R <sub>θJC</sub> (Notes 1, 3)	Steady	T <sub>C</sub> = 100°C		143	
Power Dissipation	State	T <sub>C</sub> = 25°C	$P_{D}$	200	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		100	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	28	Α
Current R <sub>θJA</sub> (Notes 1, 2, 3)	Steady	T <sub>A</sub> = 100°C		20	
Power Dissipation	State	T <sub>A</sub> = 25°C	$P_{D}$	3.8	W
R <sub>θJA</sub> (Notes 1, 2)		T <sub>A</sub> = 100°C		1.9	
Pulsed Drain Current	$T_A = 25$	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	900	Α
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			Is	166	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 16.1 A)			E <sub>AS</sub>	1271	mJ
Lead Temperature for S (1/8" from case for 10 s)		urposes	TL	260	°C

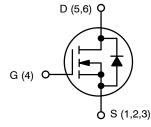
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	0.75	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	39	

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
80 V	2.1 mΩ @ 10 V	203 A



**N-CHANNEL MOSFET** 



XXXXXX = Specific Device Code

A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS				1		1	•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		80			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				39		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25 °C			10	
		V <sub>DS</sub> = 80 V	T <sub>J</sub> = 125°C			250	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub>	= 20 V			100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D =$	: 330 μA	2.0		4.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				8.0		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 20 A		1.7	2.1	mΩ
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> =15 V, I <sub>D</sub>	= 50 A		138		S
CHARGES, CAPACITANCES & GATE RE	SISTANCE						
Input Capacitance	C <sub>ISS</sub>				5530		
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz	z, V <sub>DS</sub> = 40 V		760		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				27		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 40 V; I <sub>D</sub> = 50 A			85		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 40 V; I <sub>D</sub> = 50 A			15		
Gate-to-Source Charge	$Q_GS$				26		
Gate-to-Drain Charge	$Q_{GD}$				16		
Plateau Voltage	$V_{GP}$				4.8		V
SWITCHING CHARACTERISTICS (Note 5	5)			•		•	•
Turn-On Delay Time	t <sub>d(ON)</sub>				25		
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub>	s = 64 V.		89		ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>	I <sub>D</sub> = 50 A, R <sub>G</sub> =	2.5 Ω		97		
Fall Time	t <sub>f</sub>				85		1
DRAIN-SOURCE DIODE CHARACTERIS	TICS			•		•	•
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 50 A	T <sub>J</sub> = 25°C		0.8	1.2	.,
			T <sub>J</sub> = 125°C		0.7		V
Reverse Recovery Time	t <sub>RR</sub>				76		
Charge Time	t <sub>a</sub>	$V_{GS}$ = 0 V, dIS/dt = 100 A/ $\mu$ s, $I_S$ = 50 A			36		ns
Discharge Time	t <sub>b</sub>				40		1
Reverse Recovery Charge	Q <sub>RR</sub>				82		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

5. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

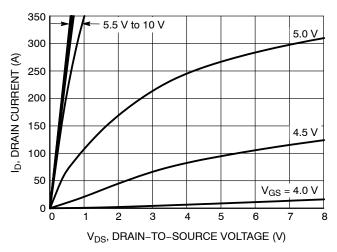


Figure 1. On-Region Characteristics

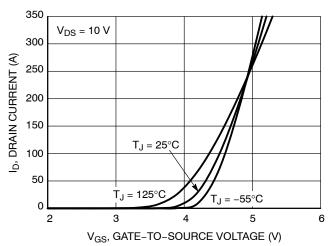


Figure 2. Transfer Characteristics

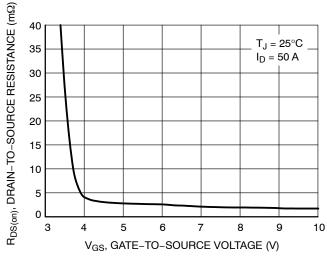


Figure 3. On-Resistance vs. Gate-to-Source Voltage

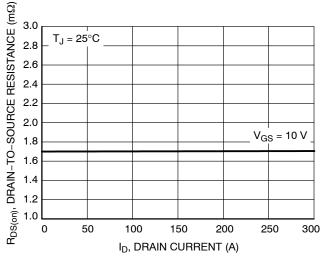


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

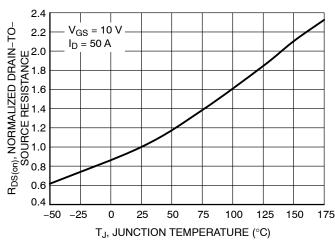


Figure 5. On–Resistance Variation with Temperature

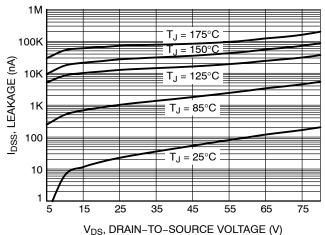


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

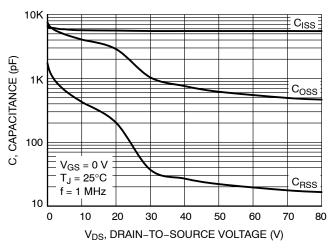


Figure 7. Capacitance Variation

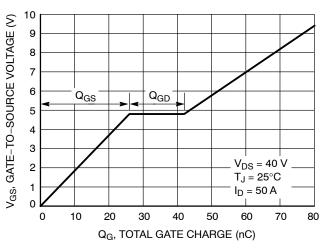


Figure 8. Gate-to-Source vs. Total Charge

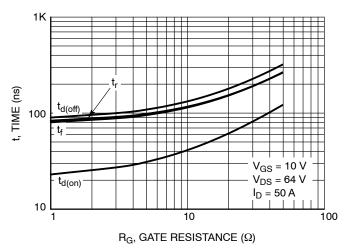


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

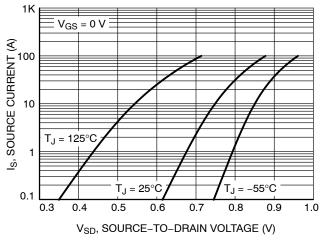


Figure 10. Diode Forward Voltage vs. Current

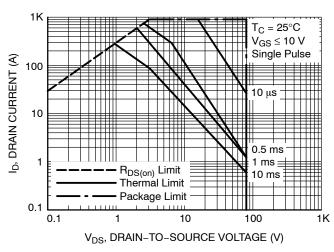


Figure 11. Maximum Rated Forward Biased Safe Operating Area

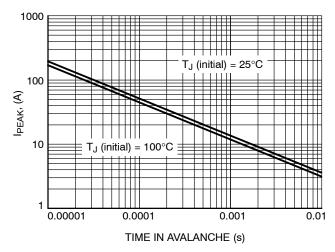


Figure 12.  $I_{\mbox{\scriptsize PEAK}}$  vs. Time in Avalanche

### **TYPICAL CHARACTERISTICS**

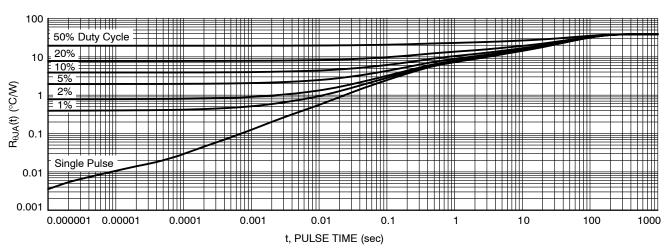


Figure 13. Thermal Response

### **DEVICE ORDERING INFORMATION**

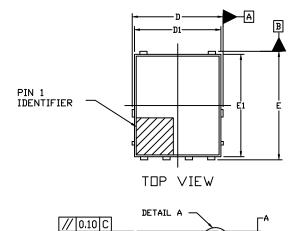
Device	Case	Marking	Package	Shipping <sup>†</sup>
NVMFS6H800NT1G	506EZ	6H800N	DFN5 (Pb-Free)	1500 / Tape & Reel
NVMFS6H800NWFT1G	507BA	800NWF	DFNW5 (Pb-Free, Wettable Flanks)	1500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### **PACKAGE DIMENSIONS**

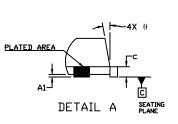
# DFNW5 5x6 (FULL-CUT SO8FL WF)

CASE 507BA **ISSUE A** 

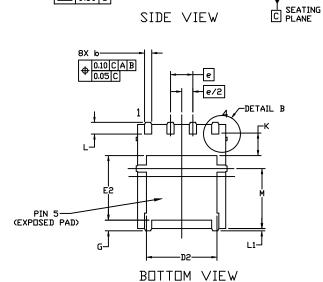




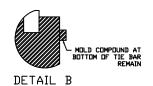
- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
  2. CONTROLLING DIMENSION: MILLIMETERS
  3. DIMENSIONS D1 AND E1 D0 NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.
  4. THIS PACKAGE CONTAINS WETTABLE FLANK DESIGN FEATURES TO A 41D IN FILLET FORMATION ON THE LEADS DURING MOUNTING.



	MILLIMETERS			
DIM	MIN.	N□M.	MAX.	
Α	0.90	1.00	1.10	
A1	0.00		0.05	
b	0.33	0.41	0.51	
С	0.23	0.28	0.33	
D	5.00	5.15	5.30	
D1	4.70	4.90	5.10	
D2	3.80	4.00	4.20	
Ε	6.00	6.15	6.30	
E1	5.70	5.90	6.10	
E2	3.45	3.65	3.85	
e		1.27 BSC	;	
G	0.51	0.575	0.71	
K	1.20	1.35	1.50	
L	0.51	0.575	0.71	
L1	0.150 REF			
М	3.00	3.40	3.80	
θ	0*		12*	



0.10 C



	2X 0.4950 4.56	
PACKAGE	2x 1.53	.53
	4X 0.75—— —	

# RECOMMENDED MOUNTING FOOTPRINT

For additional information on our Pb-Free strategy and soldering details, please download the DN Semiconductor Soldering and Mounting Techniques Reference Manual, SDLDERRM/D.

SCALE 2:1





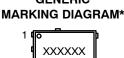
**DATE 25 AUG 2021** 

**MILLIMETERS** 

- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
  2. CONTROLLING DIMENSION: MILLIMETERS
  3. DIMENSIONS D1 AND E1 D0 NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

	d I III					
			DIM	I MIN.	N□M.	MAX.
PIN 1 IDENTIFIER —			э <b>А</b>	0.90	1.00	1.10
1	i i	i	A1	0.00		0.05
			b	0.33	0.41	0.51
٩			_ c	0.23	0.28	0.33
·		A1-J I V	ם ו	5.00	5.15	5.30
	TOP VIEW		EATING D1	4.70	4.90	5.10
	101 112 11		D2	3.80	4.00	4.20
	DETAIL A —		E	6.00	6.15	6.30
// 0.10 C	$\overline{}$		E1	5.70	5.90	6.10
4		<b>‡</b>	E2	3.45	3.80	3.85
□ 0.10 C			е		1.27 BSC	,
	SIDE VIEW	SEATING C PLANE	G	0.51	0.575	0.71
	OIDL VILW		k	1.10	1.20	1.40
8X b	-		L	0.51	0.575	0.71
⊕ 0.10 C A B 0.05 C			L1		0.125 RE	F
[ * [0.05[C]	<del>   </del> e		М	3.00	3.40	3.80
	<del>    e/2</del>		θ	0*		12*
<u>1</u> 		K	2X 0.4950-	2× 1.53-	.56 <del></del>	
i 🕏	<del></del>	PACKAGE	2X 0.25-	刑	<del> </del>	

(EXPOSED PAD) **GENERIC** BOTTOM VIEW



PACKAGE DUTLINE

2X 0.91

0.97

4X 1.00

4X 0.75-



= Year

= Work Week

Α Υ

W

ZZ

= Assembly Location

RECOMMENDED MOUNTING FOOTPRINT

\_ 1.27 PITCH

For additional information on our Pb-Free strategy and soldering details, please download the IN Semiconductor Soldering and Mounting Techniques Reference Manual, SDLDERRM/D.

= Lot Traceability \*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■" may or may not be present. Some products may not follow the Generic Marking.

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DESCRIPTION:	DFN5 5x6, 1.27P (SO-8FL)		PAGE 1 OF 1	

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